

## Very Low Power 2-Output PCIe Clock Generator

### Features

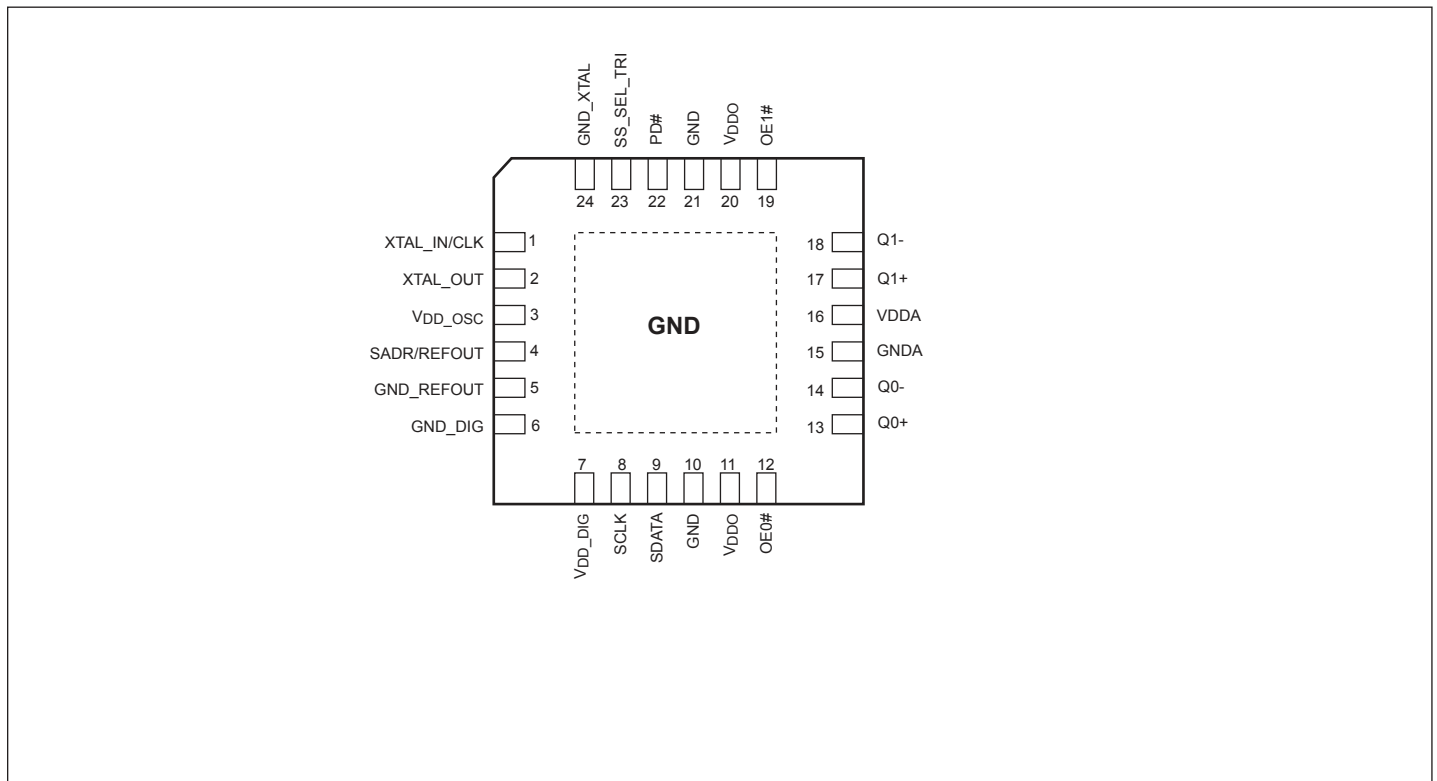
- 1.8V supply voltage
- Crystal/CMOS input: 25 MHz
- 2 differential low power HCSL outputs
- Individual output enable
- Reference CMOS output
- Programmable Slew rate and output amplitude for each output
- Differential outputs blocked until PLL is locked
- Selectable 0%, -0.25% or -0.5% spread on differential outputs
- Strapping pins or SMBus for configuration;
- 3.3V tolerant SMBus interface support
- Very low jitter outputs
  - Differential cycle-to-cycle jitter <50ps
  - Differential output-to-output skew <50ps
  - PCIe Gen1/Gen2/Gen3/Gen4 compliant
  - CMOS REFOUT phase jitter is < 1.5ps RMS
- Packaging (Pb-free & Green): 24-lead 4x4mm TQFN

### Description

The PI6CG18200 is an 2-output very low power PCIe Gen1/Gen2/Gen3/Gen4 clock generator. It uses 25MHz crystal or CMOS reference as an input to generate the 100MHz low power differential HCSL outputs with on-chip terminations. An additional buffered reference output is provided to serve as a low noise reference for other circuitry.

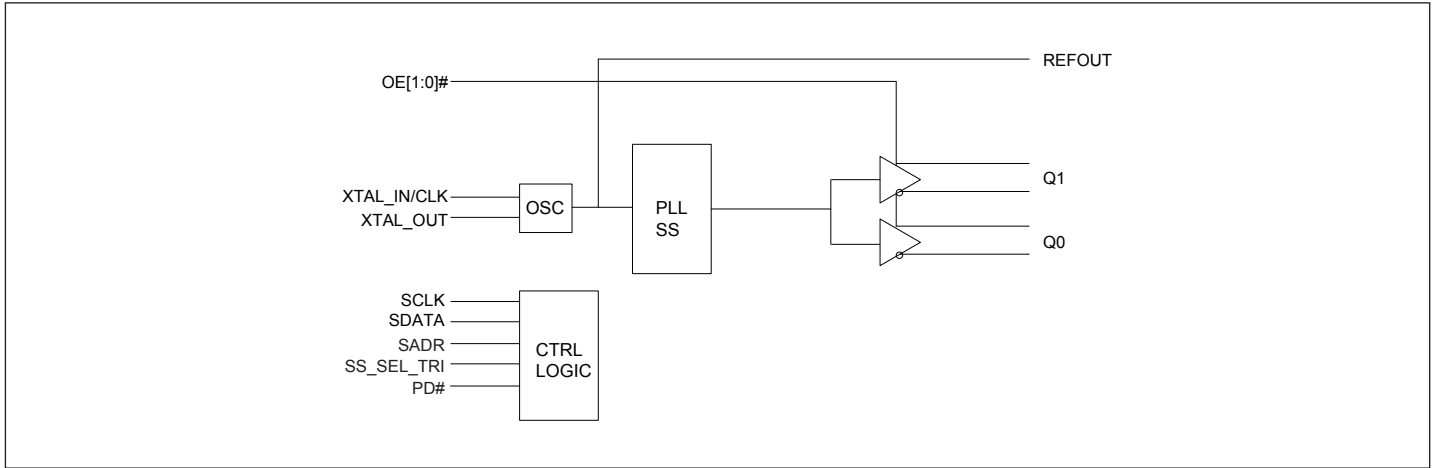
It uses Diodes Incorporated proprietary PLL design to achieve very low jitter that meets PCIe Gen1/Gen2/Gen3/Gen4 requirements. It also provides various options such as different slew rate and amplitude through strapping pins or SMBUS so that users can configure the device easily to get the optimized performance for their individual boards. The device also supports selectable spread-spectrum options to reduce EMI for various applications.

### Pin Configuration



**PI6CG18200**

**Block Diagram**



## Pin Description

Pin Number	Pin Name	Type		Description
1	XTAL_IN/CLK	Input		Crystal input or CMOS reference input
2	XTAL_OUT	Output		Crystal output
3	V <sub>DD</sub> _OSC	Power		Power supply for oscillator circuitry, nominal 1.8V
4	SADR/REFOUT	Input/ Output	CMOS	Latch to select SMBus Address or 1.8V LVCMOS REFOUT. This pin has an internal pull-down
5	GND_REFOUT	Power		Ground for REFOUT
6	GND_DIG	Power		Ground for digital circuitry
7	V <sub>DD</sub> _DIG	Power		Power supply for digital circuitry, nominal 1.8V
8	SCLK	Input	CMOS	SMBUS clock input, 3.3V tolerant
9	SDATA	Input/ Output	CMOS	SMBUS Data line, 3.3V tolerant
10, 21	GND	Power		Ground
11, 20	V <sub>DDO</sub>	Power		Power supply for differential outputs
12	OE0#	Input	CMOS	Active low input for enabling Q0 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
13	Q0+	Output	HCSL	Differential true clock output
14	Q0-	Output	HCSL	Differential complementary clock output
15	GND <sub>A</sub>	Power		Ground for analog circuitry
16	V <sub>DDA</sub>	Power		Power supply for analog circuitry
17	Q1+	Output	HCSL	Differential true clock output
18	Q1-	Output	HCSL	Differential complementary clock output
19	OE1#	Input	CMOS	Active low input for enabling Q1 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
22	PD#	Input	CMOS	Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode, subsequent high assertions exit Power Down Mode. This pin has internal pull-up resistor.
23	SS_SEL_TRI	Input	Tri-level	Latched select input to select spread spectrum amount at initial power up 1 = -0.5% spread, M = -0.25%, 0 = Spread Off
24	GND_XTAL	Power		Ground for oscillator circuit

### SMBus Address Selection Table

	SADR	Address	+Read/Write Bit
State of SADR on first application of PD#	0	1101000	X
	1	1101010	X

### Power Management Table

PD#	SMBus OE bit	OEn#	Qn+	Qn-	REFOUT
0	X	X	Low	Low	HiZ
1	1	0	Running	Running	Running
1	1	1	Low	Low	Low
1	0	X	Low	Low	Low

## Maximum Ratings

(Above which useful life may be impaired. For user guidelines, not tested.)

Storage Temperature.....	-65°C to +150°C
Junction Temperature .....	up to +125°C
Supply Voltage to Ground Potential, $V_{DDxx}$ .....	-0.5V to +2.5V
Input Voltage .....	-0.5V to $V_{DD}+0.5V$ , not exceed 2.5V
SMBus, Input High Voltage .....	3.6V
ESD Protection (HBM) .....	2000 V

**Note:** Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

## Operating Conditions

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min..	Typ.	Max.	Units
$V_{DDO}$ , $V_{DDA}$ , $V_{DD\_OSC}$ , $V_{DD\_DIG}$	Power Supply Voltage		1.7	1.8	1.9	V
$I_{DDA}$	Analog Power Supply Current	All outputs active @100MHz		7	8	mA
$I_{DD}$	Power Supply Current	All $V_{DD}$ , except $V_{DDA}$ All outputs active @100MHz		15	18	mA
$I_{DD\_WL}$	Power Supply Wake-on-LAN <sup>1</sup> Current	All $V_{DD}$ , Q outputs off, REF output running		1.5	2	mA
$I_{DD\_PD}$	Power Supply Power Down <sup>2</sup> Current	All outputs off		0.6	1	mA
$T_A$	Ambient Temperature	Industrial grade	-40		85	°C

### Note:

1. Wake-on-LAN mode: PD# = '0' Byte 3, bit 5 = '1'
2. Power down mode: PD# = '0' Byte 3, bit 5 = '0'

### Input Electrical Characteristics

Symbol	Parameters	Conditions	Min.	Typ.	Max.	Units
R <sub>pu</sub>	Internal pull up resistance			120		KΩ
R <sub>dn</sub>	Internal pull down resistance			120		KΩ
C <sub>XTAL</sub>	Internal capacitance on X_IN and X_OUT pins			5		pF
L <sub>PIN</sub>	Pin inductance				7	nH

### Crystal Characteristic

Parameters	Description	Min.	Typ	Max.	Units
OSCmode	Mode of Oscillation	Fundamental			
FREQ	Frequency		25		MHz
ESR <sup>1</sup>	Equivalent Series Resistance			50	Ω
C <sub>load</sub>	Load Capacitance		8		pF
C <sub>shunt</sub>	Shunt Capacitance			7	pF
	Drive Level			300	uW

**Note:**

1. ESR value is dependent upon frequency of oscillation

### SMBus Electrical Characteristics

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Typ.	Max.	Units
V <sub>DDSMB</sub>	Nominal bus voltage		1.7		3.6	V
V <sub>IHSMB</sub>	SMBus Input High Voltage	SMBus, V <sub>DDSMB</sub> = 3.3V	2.1		3.6	V
		SMBus, V <sub>DDSMB</sub> < 3.3V	0.65 V <sub>DDSMB</sub>			
V <sub>ILSMB</sub>	SMBus Input Low Voltage	SMBus, V <sub>DDSMB</sub> = 3.3V			0.6	V
		SMBus, V <sub>DDSMB</sub> < 3.3V			0.6	
I <sub>SMBSINK</sub>	SMBus sink current	SMBus, at V <sub>OLSMB</sub>	4			mA
V <sub>OLSMB</sub>	SMBus Output Low Voltage	SMBus, at I <sub>SMBSINK</sub>			0.4	V
f <sub>MAXSMB</sub>	SMBus operating frequency	Maximum frequency			400	kHz
t <sub>RMSB</sub>	SMBus rise time	(Max V <sub>IL</sub> - 0.15) to (Min V <sub>IH</sub> + 0.15)			1000	ns
t <sub>FMSB</sub>	SMBus fall time	(Min V <sub>IH</sub> + 0.15) to (Max V <sub>IL</sub> - 0.15)			300	ns

### Spread Spectrum Characteristic

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Typ.	Max.	Units
f <sub>MOD</sub>	SS Modulation Frequency	Triangular modulation	30	31.6	33	kHz

## LVC MOS DC Electrical Characteristics

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Typ.	Max.	Units
$V_{IH}$	Input High Voltage	Single-ended inputs, except SMBus	0.75 $V_{DD}$		$V_{DD}$ +0.3	V
$V_{IM}$	Input Mid Voltage	SS_SEL_TRI	$0.4V_{DD}$	$0.5V_{DD}$	$0.6V_{DD}$	V
$V_{IL}$	Input Low Voltage	Single-ended inputs, except SMBus	-0.3		0.25 $V_{DD}$	V
$I_{IH}$	Input High Current	Single-ended inputs, $V_{IN} = V_{DD}$			20	$\mu A$
$I_{IL}$	Input Low Current	Single-ended inputs, $V_{IN} = 0V$	-20			$\mu A$
$I_{IH}$	Input High Current	Single-ended inputs with pull up / pull down resistor, $V_{IN} = V_{DD}$			220	$\mu A$
$I_{IL}$	Input Low Current	Single-ended inputs with pull up / pull down resistor, $V_{IN} = 0V$	-220			$\mu A$
$V_{OH}$	Output High Voltage	REFOUT, except SMBus; $I_{OH} = -2mA$	$V_{DD}$ -0.45			V
$V_{OL}$	Output Low Voltage	REFOUT, except SMBus; $I_{OH} = 2mA$			0.45	V
$R_{OUT}$	CMOS Output impedance			20		$\Omega$
$C_{IN}$	Input Capacitance		1.5		5	pF

## LVC MOS AC Characteristics

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Typ.	Max.	Units
$f_{INPUT}$	Input Frequency	XTAL_IN/CLK	23	25	27	MHz
$t_{RIN}$	Input rise time	Single-ended inputs			5	ns
$t_{FIN}$	Input fall time	Single-ended inputs			5	ns
$t_{STAB}$	Clock stabilization	From Power-Up and after input clock stabilization or de-assertion of PD# to 1st clock		0.6	1.8	ms
$t_{OELAT}$	Output enable latency	Q start after OE# assertion Q stop after OE# deassertion	1		3	clocks
$t_{PDLAT}$	PD# de-assertion	Differential outputs enable after PD# de-assertion			300	us
$t_{PERIOD}$	REFOUT clock period	REFOUT, assume input is at 25MHz		40		ns
$f_{ACC}$	REFOUT frequency accuracy <sup>1</sup>	REFOUT, long term accuracy to input		0		ppm
$t_{SLEW}$	REFOUT slew rate <sup>1</sup>	Byte 3 = 1F, 20% to 80% of $V_{DDREF}$		1	2.5	V/ns
		Byte 3 = 5F, 20% to 80% of $V_{DDREF}$		1.6	2.5	V/ns
		Byte 3 = 9F, 20% to 80% of $V_{DDREF}$		2.0	2.5	V/ns
		Byte 3 = DF, 20% to 80% of $V_{DDREF}$		2.1	2.5	V/ns
$t_{DC}$	REFOUT Duty Cycle <sup>1</sup>	$V_T = V_{DD} / 2$ V, driven by a Xtal	45	50	55	%

### LVCMOS AC Characteristics (Cont.)

Symbol	Parameters	Condition	Min.	Typ.	Max.	Units
$t_{DCDIS}$	REFOUT Duty Cycle Distortion	$V_T = V_{DD} / 2$ V, driven by an external source	0	2	4	%
$t_{JITCC}$	REFOUT cycle-cycle jitter	$V_T = V_{DD} / 2$ V, driven by a Xtal		20	250	ps
$t_{JITPH}$	REFOUT phase jitter	12kHz to 5MHz, RMS, driven by a Xtal		0.68	1.5	ps
$t_{JITN}$	Noise floor	1kHz offset, driven by a Xtal		-130	-105	dBc
		10kHz offset to Nyquist, driven by a Xtal		-140	-120	dBc

**Note:**

1. Guaranteed by design and characterization, not 100% tested in production

### HCSL Output Characteristics

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Typ.	Max.	Units
$V_{OH}$	Output Voltage High <sup>1</sup>	Statistical measurement on single-ended signal using oscilloscope math function	660	784	900	mV
$V_{OL}$	Output Voltage Low <sup>1</sup>		-150		150	mV
$V_{OMAX}$	Output Voltage Maximum <sup>1</sup>	Measurement on single ended signal using absolute value		816	1150	mV
$V_{OMIN}$	Output Voltage Minimum <sup>1</sup>		-300	-15		mV
$V_{OSWING}$	Output Swing Voltage <sup>1,2,3</sup>	Scope averaging off	300	1551		mV
$V_{OC}$	Output Cross Voltage <sup>1,2,4</sup>		250	400	550	mV
$DV_{OC}$	$V_{OC}$ Magnitude Change <sup>1,2,5</sup>			14	140	mV

**Note:**

- At default SMBUS amplitude settings
- Guaranteed by design and characterization, not 100% tested in production
- Measured from differential waveform
- This one is defined as voltage where  $Q+ = Q-$  measured on a component test board and only applied to the differential rising edge
- The total variation of all  $V_{cross}$  measurements in any particular system. This is a subset of  $V_{cross\_min/max}$  allowed.

### HCSL Output AC Characteristics

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Typ.	Max.	Units
$f_{OUT}$	Output Frequency			100		MHz
$t_{RF}$	Slew rate <sup>1,2,3</sup>	Scope averaging on fast setting	2.9	3.1	5.7	V/ns
		Scope averaging on slow setting	1.1	2.0	2.5	V/ns
$D_{TRF}$	Slew rate matching <sup>1,2,4</sup>	Scope averaging on		3	20	%
$t_{DC}$	Duty Cycle <sup>1,2</sup>	Measured differentially, PLL Mode	45	50	55	%
$t_{SKEW}$	Output Skew <sup>1,2</sup>	Averaging on, $V_T = 50\%$		34	50	ps
$t_{j-c-c}$	Cycle to cycle jitter <sup>1,2</sup>			14	55	ps
$t_{STARTUP}$	Start up time				10	ms
$t_{LOCK}$	PLL lock time				20	ms



**HCSL Output AC Characteristics (continued)**

Symbol	Parameters	Condition	Min.	Typ.	Max.	Units
t <sub>JPHASE</sub>	Integrated phase jitter (RMS) 1,5,6	PCIe Gen 1	20	25	86	ps
		PCIe Gen 2 Low Band, 10kHz < f < 1.5MHz	0.8	0.9	3.0	ps
		PCIe Gen 2 High Band, 1.5MHz < f < Nyquist (50MHz)	1.5	1.6	3.1	ps
		PCIe Gen 3 Common Clock Architecture (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.4	0.5	1.0	ps
		PCIe Gen 4 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.25	0.3	0.5	ps

**Note:**

1. Guaranteed by design and characterization, not 100% tested in production
2. Measured from differential waveform
3. Slew rate is measured through the V<sub>swing</sub> voltage range centered around differential 0V, within +/-150mV window
4. Slew rate matching is measured using a +/-75mV window centered on the differential zero
5. See <http://www.pcisig.com> for complete specs
6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of 10<sup>-12</sup>

**Differential Output Clock Periods - Spread Spectrum Disabled <sup>1, 2</sup>**

Center Freq. MHz	Measurement Window							Units
	1 clock	1 us	0.1 s	0.1 s	0.1 s	1 us	1 clock	
	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long-term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	
100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns

**Differential Output Clock Periods - Spread Spectrum Enabled <sup>1, 2</sup>**

Center Freq. MHz	Measurement Window							Units
	1 clock	1 us	0.1 s	0.1 s	0.1 s	1 us	1 clock	
	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long-term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	
99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns

**Note:**

1. Guaranteed by design and characterization, not 100% tested in production
2. All long term accuracy and clock period specifications are guaranteed assuming REF is trimmed to 25.00MHz

## SMBus Serial Data Interface

PI6CG18200 is a slave only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below.

Read and write block transfers can be stopped after any complete byte transfer.

### Address Assignment

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	0	SADR	0	1/0

Note: SMBus address is latched on SADR pin

### How to Write

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit		8 bits	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte location = N	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack	.....	Data Byte (N+X-1)	Ack	Stop bit

### How to Read

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte location = N	Ack	Repeat Start bit	Address	R(1)	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack

	8 bits	1 bit	1 bit
.....	Data Byte (N+X-1)	NAck	Stop bit

### Byte 0: Output Enable Register <sup>1</sup>

Bit	Control Function	Description	Type	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	Reserved			1		
2	Q1_OE	Q1 output enable	RW	1	Low/Low	Enabled
1	Q0_OE	Q0 output enable	RW	1	Low/Low	Enabled
0	Reserved			1		

**Note:**

1. A low on these bits will override the OE# pins and force the differential outputs to Low/Low states

### Byte 1: SS Readback and Control Register

Bit	Control Function	Description	Type	Power Up Condition	0	1
7	SSENRB1	SS Enable Readback Bit1	R	Latch	'00' for SS_SEL_TRI = '0',	
6	SSENRB0	SS Enable Readback Bit0	R	Latch	'01' for SS_SEL_TRI = 'M', '11' for SS_SEL_TRI = '1'	
5	SSEN_SWCTR	Enable SW control of SS	RW	0	Values in B1[7:6] control SS amount	Values in B1[4:3] control SS amount
4	SSENSW1	SS enable SW control Bit1	RW <sup>1</sup>	0	'00' = SS off, '01' = -0.25% SS, '10' = Reserved, '11' = -0.5% SS	
3	SSENSW0	SS enable SW control Bit0	RW <sup>1</sup>	0		
2	Reserved			1		
1	Amplitude1	Control output amplitude	RW	1	'00' = 0.6V, '01' = 0.7V, '10' = 0.8V, '11' = 0.9V	
0	Amplitude0		RW	0		

**Note:**

1. B1[5] must be set to a 1 for these bits to have any effect on the part.

### Byte 2: Differential Output Slew Rate Control Register

Bit	Control Function	Description	Type	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	Reserved			1		
2	SLEWRATECTR_Q1	Control slew rate of Q1	RW	1	Slow setting	Fast setting
1	SLEWRATECTR_Q0	Control slew rate of Q0	RW	1	Slow setting	Fast setting
0	Reserved			1		

### Byte 3: REF Control Register

Bit	Control Function	Description	Type	Power Up Condition	0	1
7	REFSLEWRATE	Slew rate control for REF	RW	0	'00' = 0.9V/ns '01' = 1.3V/ns, '10' = 1.6V/ns, '11' = 1.8V/ns	
6			RW	1		
5	REF_PDSTATE	Wake-on-Lan enable for REF	RW	0	REF = 'Low'	REF = running
4	REF_OE	Output enable for REF	RW	1	REF = "Low"	REF = running
3	Reserved			1		
2	Reserved			1		
1	Reserved			1		
0	Reserved			1		

### Byte 4: Reserved

Bit	Control Function	Description	Type	Power Up Condition	0	1
7:0	Reserved			1		

### Byte 5: Revision and Vendor ID Register

Bit	Control Function	Description	Type	Power Up Condition	0	1
7	RID3	Revision ID	R	0	rev = 0000	
6	RID2		R	0		
5	RID1		R	0		
4	RID0		R	0		
3	PVID3	Vendor ID	R	0	Pericom = 0011	
2	PVID3		R	0		
1	PVID3		R	1		
0	PVID3		R	1		

### Byte 6: Device Type/Device ID Register

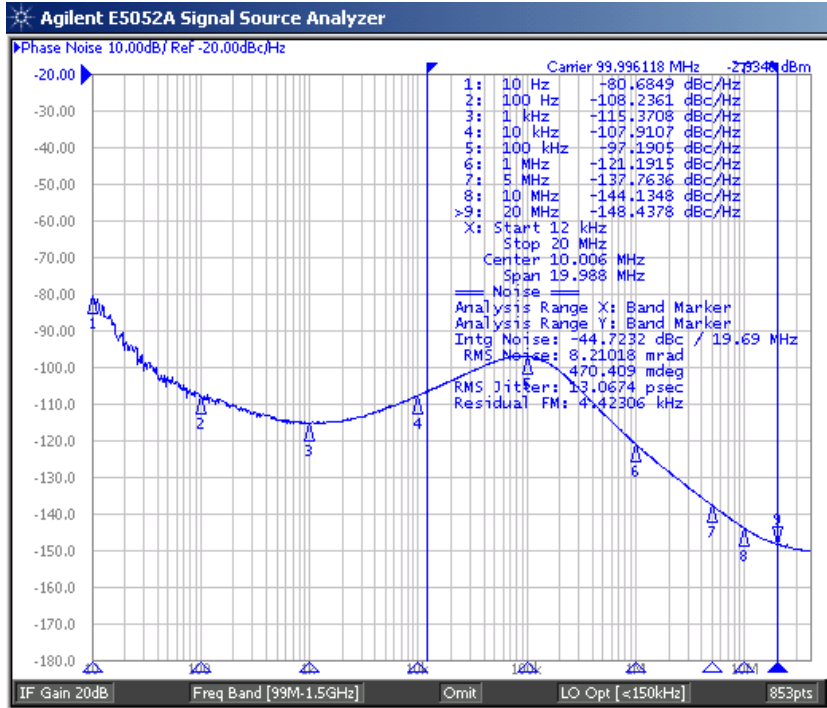
Bit	Control Function	Description	Type	Power Up Condition	0	1
7	DTYPE1	Device type	R	0	'00' = CG, '01' = ZDB, '10' = Reserve, '11' = ZDB	
6	DTYPE0		R	0		
5	DID5	Device ID	R	0	000010 binary, 02Hex	
4	DID4		R	0		
3	DID3		R	0		
2	DID2		R	0		
1	DID1		R	1		
0	DID0		R	0		

### Byte 7: Byte Count Register

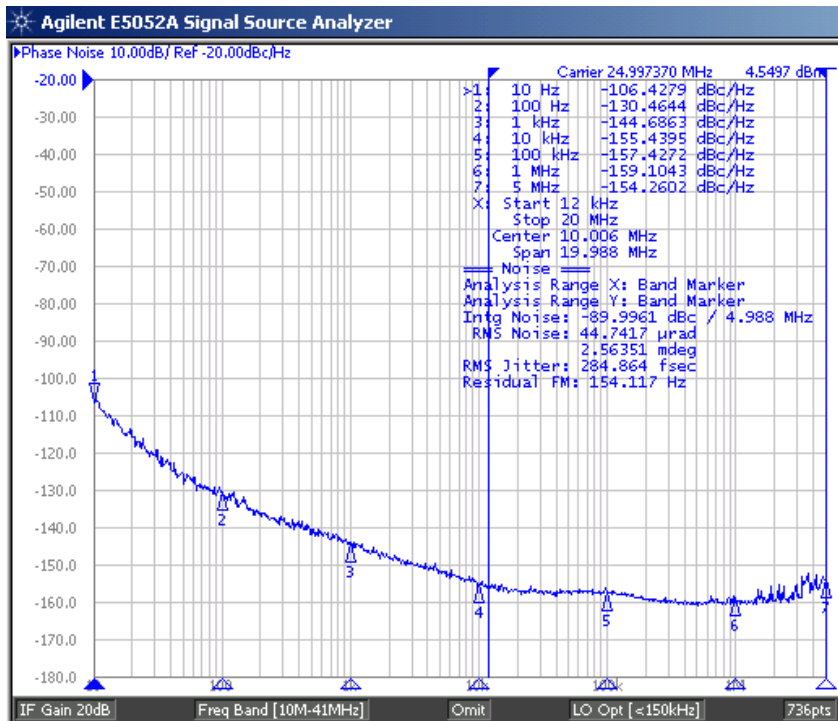
Bit	Control Function	Description	Type	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	BC4	Byte count programming	RW	0	Writing to this register will configure how many bytes will be read back, default is 8 bytes	
3	BC3		RW	1		
2	BC2		RW	0		
1	BC1		RW	0		
0	BC0		RW	0		

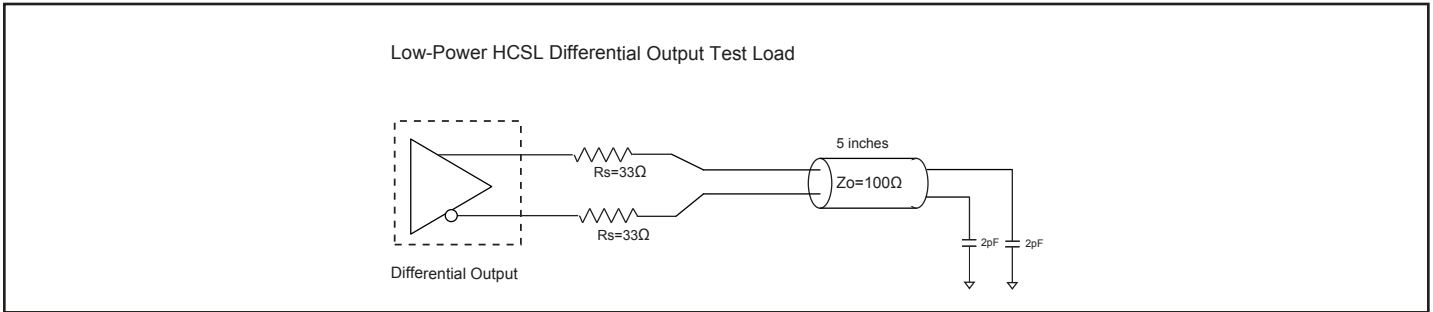
**Plots**

**100MHz HCSL Clock**



**25MHz CMOS Clock**

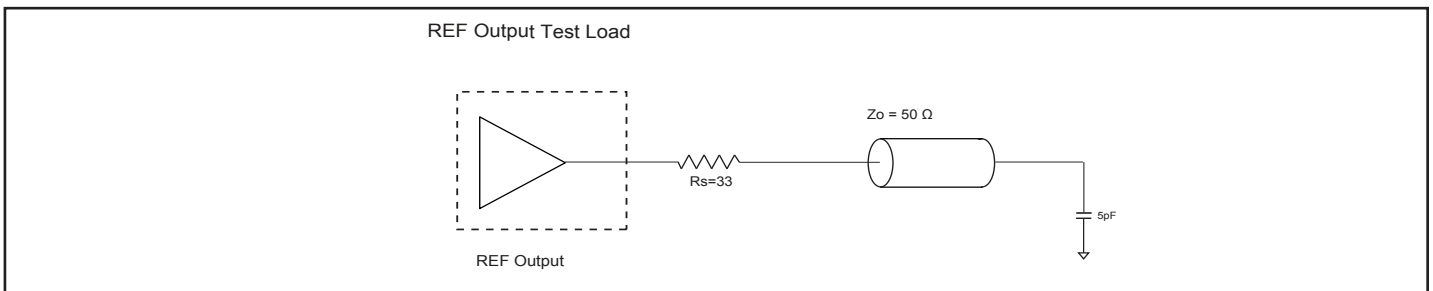




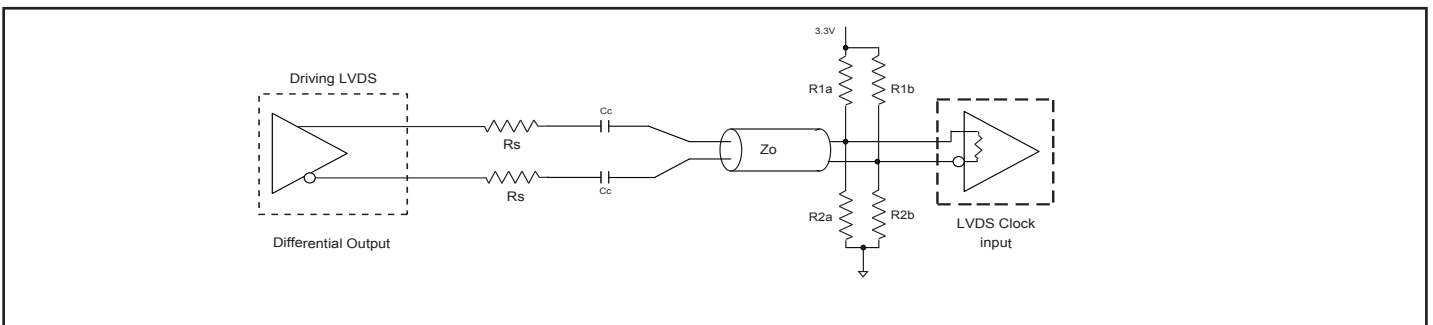
**Figure 1. Low Power HCSL Test Circuit**

**Alternate Differential Output Terminations**

$R_s$	$Z_o$	Unit
27	85	$\Omega$



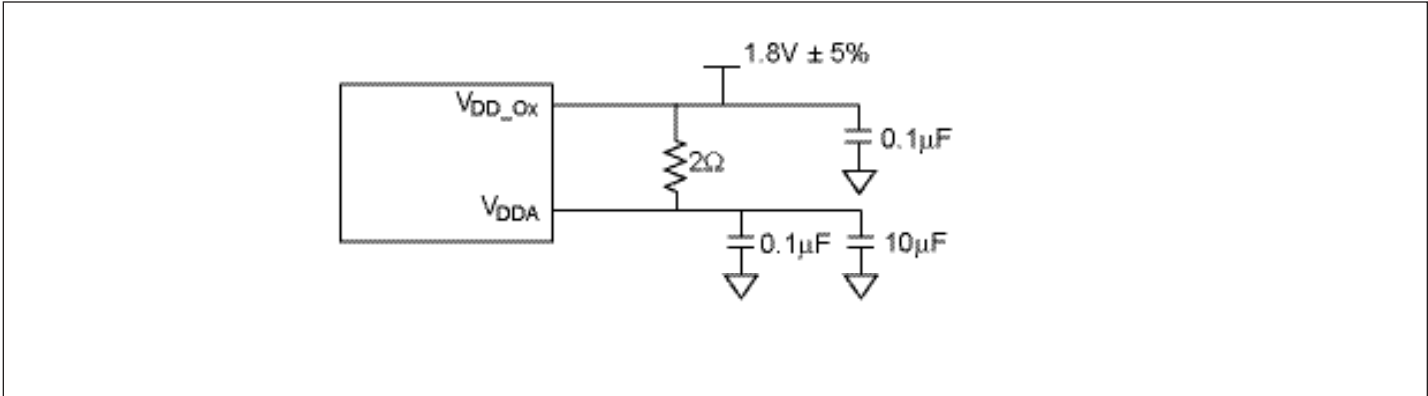
**Figure 2. CMOS REF Test Circuit**



**Figure 3. Differential Output driving LVDS**

**Alternate Differential Output Terminations**

Component	Receiver with termination	Receiver without termination	Unit
$R_{1a}, R_{1b}$	10,000	140	$\Omega$
$R_{2a}, R_{2b}$	5,600	75	$\Omega$
$C_c$	0.1	0.1	$\mu F$
$V_{CM}$	1.2	1.2	V



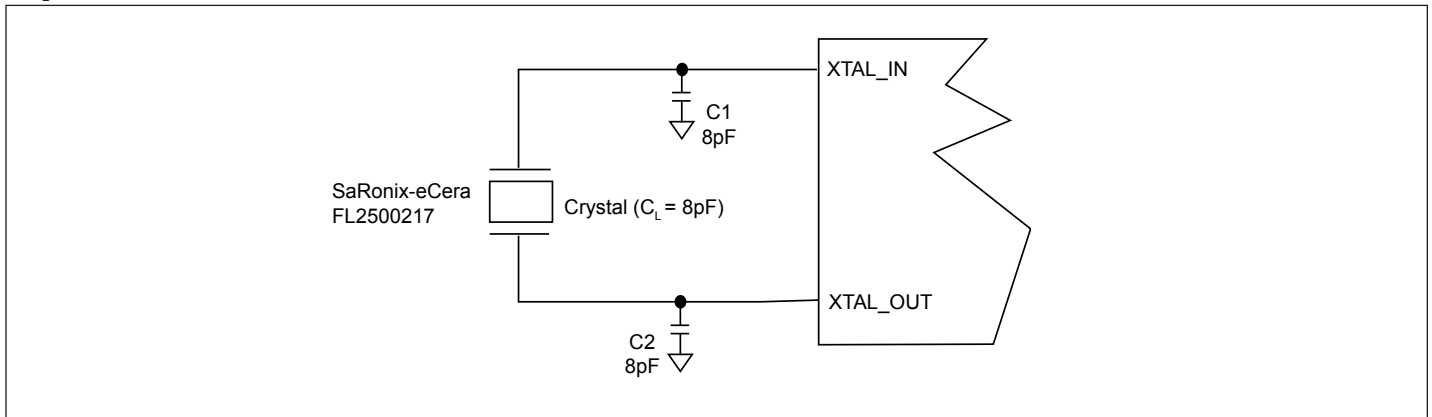
**Figure 4. Power Supply Filter**



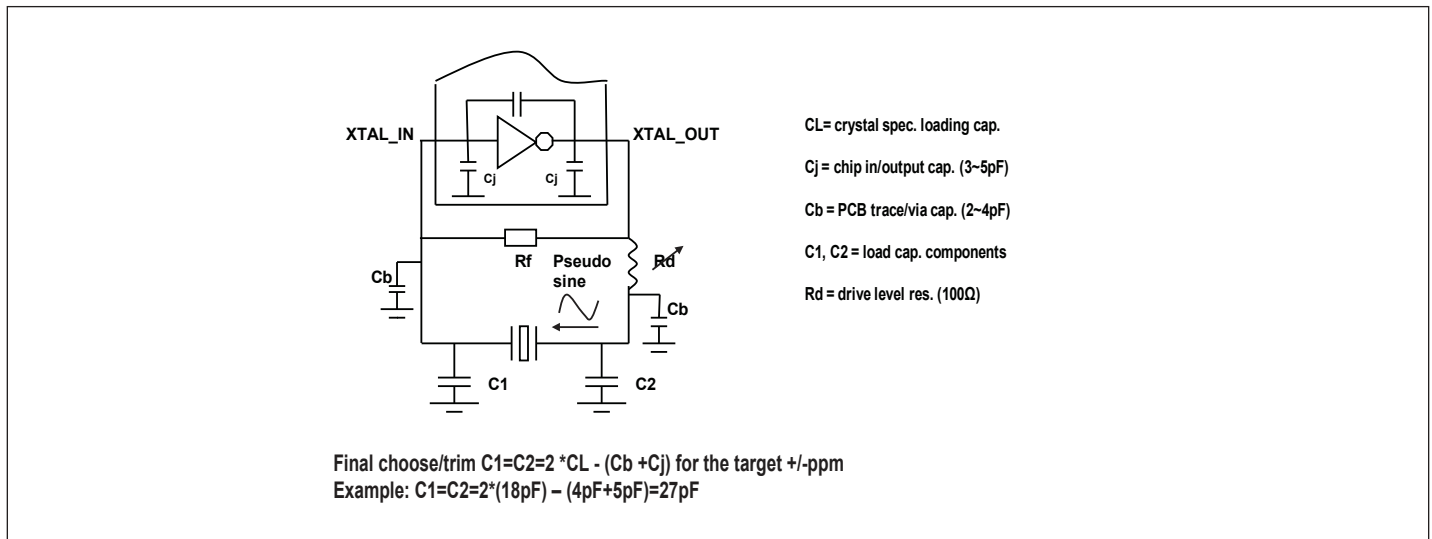
## Crystal circuit connection

The following diagram shows PI6CG18200 crystal circuit connection with a parallel crystal. For the  $CL=8\text{pF}$  crystal, it is suggested to use  $C1=8\text{pF}$ ,  $C2=8\text{pF}$ .  $C1$  and  $C2$  can be adjusted to fine tune to the target ppm of crystal oscillator according to different board layouts based on the following formular in the Crystal Capacitor Calculation diagram.

## Crystal Oscillator Circuit



## Crystal Capacitor Calculation

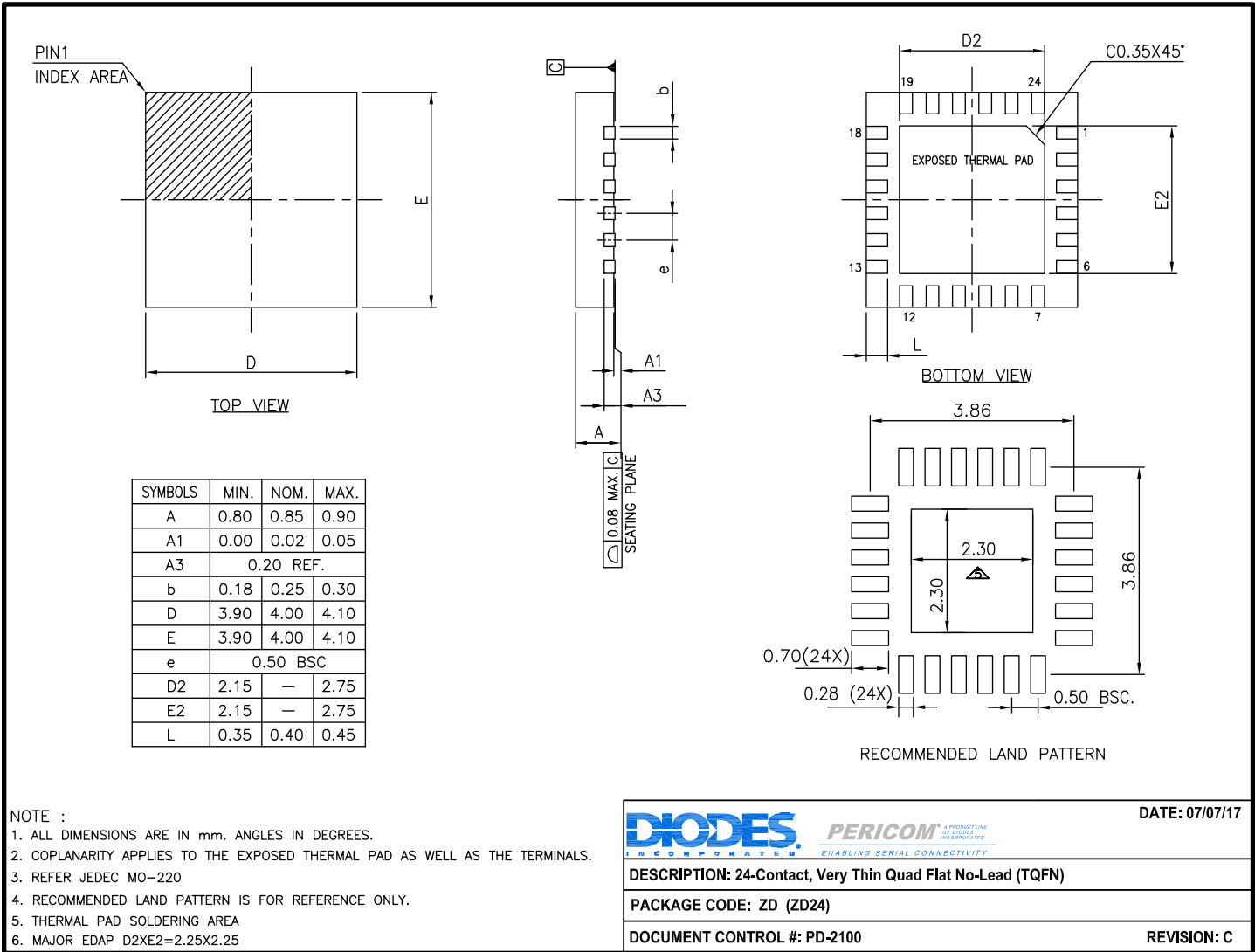


## Recommended Crystal Specification

Pericom recommends:

- a) FL2500217, SMD 3.2x2.5(4P), 25MHz,  $CL=8\text{pF}$ , +/-20ppm, <http://www.pericom.com/pdf/datasheets/se/FL.pdf>

**Packaging Mechanical: 24-Pin TQFN (ZD)**



17-0533

**Note:**

**Note:** For latest package info, please check: <https://www.diodes.com/design/support/packaging/pericom-packaging/>

**Ordering Information<sup>(1-3)</sup>**

Ordering Code	Package Code	Package Description	Operating Temperature
PI6CG18200ZDIEX	ZD	24-Pin, Pb-free & Green (TQFN), Tape & Reel	Industrial

**Notes:**

- Thermal characteristics can be found on the company web site at <https://www.diodes.com/design/support/packaging/pericom-packaging/>
- E = Pb-free and Green
- Adding an X suffix = Tape/Reel

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